

Sheet 1 of 2

INFORMATION DISCLOSURE
CITATION

(Use several sheets if necessary)

ATTY. DOCKET NO.

4105-18

APPLICANT

CHO et al.

FILING DATE

July 9, 2003

SERIAL NO.

10/615,600

TC/A.U.

2627

U.S. PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
/JH/	2004/0263185	12/2004	Cho et al.	324	636	
	2004/0114913	06/2004	Kume	386	125	
	2003/0053400	03/2003	Cho et al.	369	126	
	2004/0027935	02/2004	Cho et al.	369	126	
	2003/0021213	01/2003	Hagiwara, Yoshiaki	369	101	
	4,320,491	03/1982	Rustman, James C.	369	126	
	5,418,029	05/1995	Yamamoto et al.	428	64.2	
	5,481,527	01/1996	Kasanuki et al.	369	126	
	5,646,932	07/1997	Kuribayashi et al.	369	126	
	5,914,920	06/1999	Yokogawa	369	275.3	
	5,946,284	08/1999	Chung et al.	369	126	
	6,477,132	11/2002	Azuma et al.	369	126	
	6,510,130	01/2003	Hayashi et al.	369	275.3	
	6,515,957	02/2003	Newns et al.	369	126	
	6,653,630	11/2003	Rosenman et al.	250	306	
	6,762,402	07/2004	Choi et al.	250	234	
	6,841,220	01/2005	Onoe et al.	428	66.7	
	6,912,193	06/2005	Cho et al.	369	126	
	6,965,545	11/2005	Hino et al.	369	13.54	
	7,065,033	06/2006	Onoe et al.	369	126	
	7,149,180	12/2006	Onoe et al.	369	276	

FOREIGN PATENT DOCUMENTS

DOCUMENT	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES NO
/JH/ 2003085969	03/2003	JP			ABSTRACT
/JH/ 08-075806	03/1996	JP			ABSTRACT
/JH/ 10-334525	12/1998	JP			ABSTRACT
/JH/ 56-107338	08/1981	JP			ABSTRACT

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent pages, etc.)

/JH/	62th Japan Society of Applied Physics Lecture Meeting (2001.9 Aichi Institute of Technology) 12p-ZR-2.
------	--

*Examiner

/Joseph Haley/

Date Considered

05/09/2007

Examiner: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to application.

Sheet 2 of 2

INFORMATION DISCLOSURE
CITATION

ATTY. DOCKET NO.

SERIAL NO.

4105-18

10/615,600

APPLICANT

CHO et al.

(Use several sheets if necessary)

FILING DATE

TC/A.U.

July 9, 2003

2627

U.S. PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
/JH/	5,488,602	01/1996	Yamano et al.	369	126	
	5,808,977	09/1998	Koyanagi et al.	369	127	
	6,197,989	03/2001	Furukawa et al.	556	450	
	2005/0122886	06/2005	Takahashi et al.	369	126	
	2005/0098895	05/2005	Maeda et al.	369	13.01	
	2005/0098532	05/2005	Onoe et al.	216	22	
	20050047288	03/2005	Maeda et al.	369	53.25	
	2004/0252621	12/2004	Cho et al.	369	126	
	2004/0105380	06/2004	Cho et al.	369	126	
	2004/0105373	06/2004	Maeda et al.	369	101	
	2004/0090903	05/2004	Cho et al.	369	126	
	20040042351	03/2004	Onoe et al.	369	13.01	
	20020131669	09/2002	Onoe et al.	385	14	
	20020118906	08/2002	Onoe	385	14	
	20020105249	08/2002	Yoshida et al.	310	311	

FOREIGN PATENT DOCUMENTS

								TRANSLATION	
DOCUMENT			DATE	COUNTRY	CLASS	SUBCLASS	YES	NO	
/JH/		57-200956	12/1982	JP			ABSTRACT		
/JH/		1 484 256	09/1977	GB					

OTHER DOCUMENTS (including Author, Title, Date, Pertinent pages, etc.)

/JH/	Kazuta et al, "Determination of crystal polarities of piezoelectric thin film using scanning nonlinear dielectric microscopy", Journal of European Ceramic Society 21 (2001) 1581-1584.
/JH/	The Institution of Electrical Engineers, Stevenage, GB; 1 June 2002; Hiranaga et al, "Nano-sized inverted domain formation in stoichiometric LiTaO ₃ /single crystal using Scanning Nonlinear Dielectric Microscopy", XP002292217.
/JH/	Cho et al, "Scanning nonlinear dielectric microscopy with nanometer resolution", Journal of European Ceramic Society 21 (2001) 2131-2134.
/JH/	Cho et al., "Nano domain engineering using scanning nonlinear dielectric microscopy, October 29, 2001, IEE-NANO 2001, pages 352-357.

*Examiner

/Joseph Haley/

Date Considered

05/09/2007

Examiner: Initial if reference considered, whether or not citation is in conformance with MPEP 608; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to application.